

OCXO Part No: OS560-2005-018

Issue 2; 6th May 2022

Features

- Temperature stability ± 5 ppb
- Low phase noise
- Frequency 20MHz
- Low pre-aged options available
- The flexible nature of the design means that variations to suit almost any application can be developed to meet individual customer requirements



Option A

- Temperature stability: ± 5 ppb over (0 to $+50$) $^{\circ}$ C
- Output: Sinewave 7dBm nominal
- Voltage: 12.0V
- Warm up current: 220mA
- Quiescent current: 120mA

Phase Noise (typical)

- $F_{0}+10$ Hz -128 dBc/Hz
- $F_{0}+100$ Hz -145 dBc/Hz
- $F_{0}+1$ KHz -155 dBc/Hz
- $F_{0}+10$ KHz -160 dBc/Hz
- $F_{0}+100$ KHz -168 dBc/Hz

Values based on 10MHz unit

Voltage / Load change

- $\pm 5\%$ supply voltage change: ± 2 ppb
- $\pm 10\%$ load change: ± 10 ppb

Ageing

After 30 days continuous operation:

- Per day: ± 0.1 ppb max.
- Per year: ± 50 ppb max.
- Warm up time: 5 minutes to within 0.1 ppm

Voltage Trim

- ± 0.5 ppm minimum
- Trim impedance 50K Ω

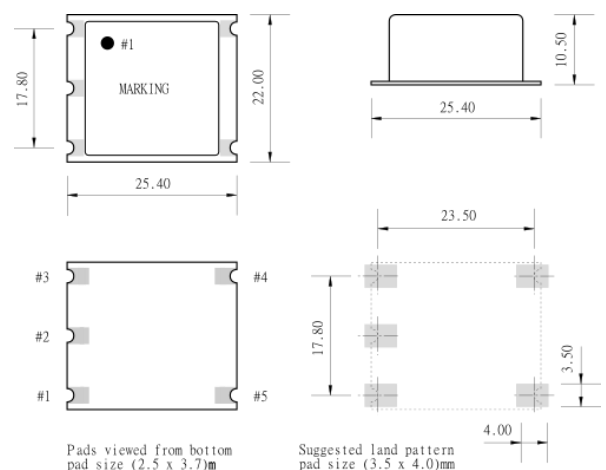
Reference Options

- 4.5V

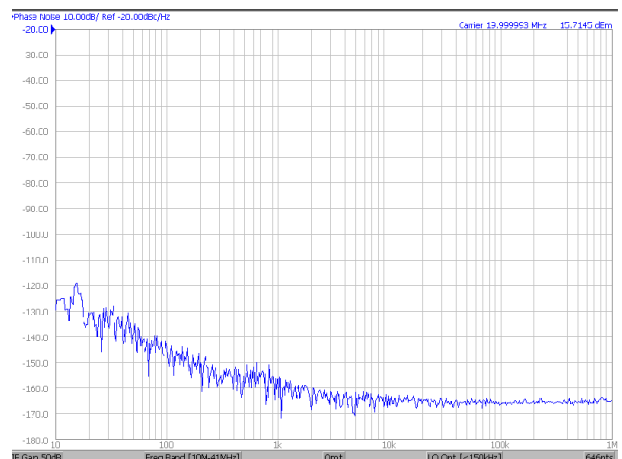
Environmental

- Electrostatic-Sensitive Device (ESD)
- Storage Temperature Range: (-40 to $+125$) $^{\circ}$ C
- Mechanical shock: MIL standard 202, method 213, condition J

Dimensions (mm)



Phase Noise Plot



- Thermal shock: MIL standard 202, method 107, condition A
- Vibration: MIL standard 202, method 204, condition B
- Solderability: 5 seconds maximum at 230°C
- 3 seconds maximum at 350°C

Compliance

- RoHS Status (2011/65/EU) - Compliant
- REACH Status - Compliant

Packaging

- Pack Style: Bulk

Ordering Information

- Unique customer part number and custom specification issued with each application
- OCXO Part No: OS560-2005-018
- Frequency: 20MHz

Test Circuit - Sinewave

